

# Measurement of $B(t \rightarrow Wb)/B(t \rightarrow Wq)$ at $D\emptyset$



**Daekwang Kau**  
**Florida State University**  
**DPF 2006, Hawaii**  
**October 30, 2006**





# Motivation

- $B(t \rightarrow Wb) \sim 100\%$  (from  $V_{tb}$ ) in the Standard Model

- We can write the ratio  $R = B(t \rightarrow Wb) / B(t \rightarrow Wq)$

$$R = \frac{|V_{tb}|^2}{|V_{tb}|^2 + |V_{ts}|^2 + |V_{td}|^2} = |V_{tb}|^2$$

- The CKM matrix element  $|V_{tb}|$  is constrained based on the assumptions : **1. The CKM matrix is unitary 2. Quark has the three generation structure**

- $|V_{tb}|$  is bounded between 0.9990 and 0.9992

- R measurement analysis provides a cross check of the assumptions and the SM prediction

- A deviated value of R could lead us new physics such as a fourth quark generation



# Top Quark and Background

## Top-pair production

### Lepton + jets

- One W decays hadronically
- One W decays leptonically

### Dilepton

- Both Ws decay leptonically

## W+Jets

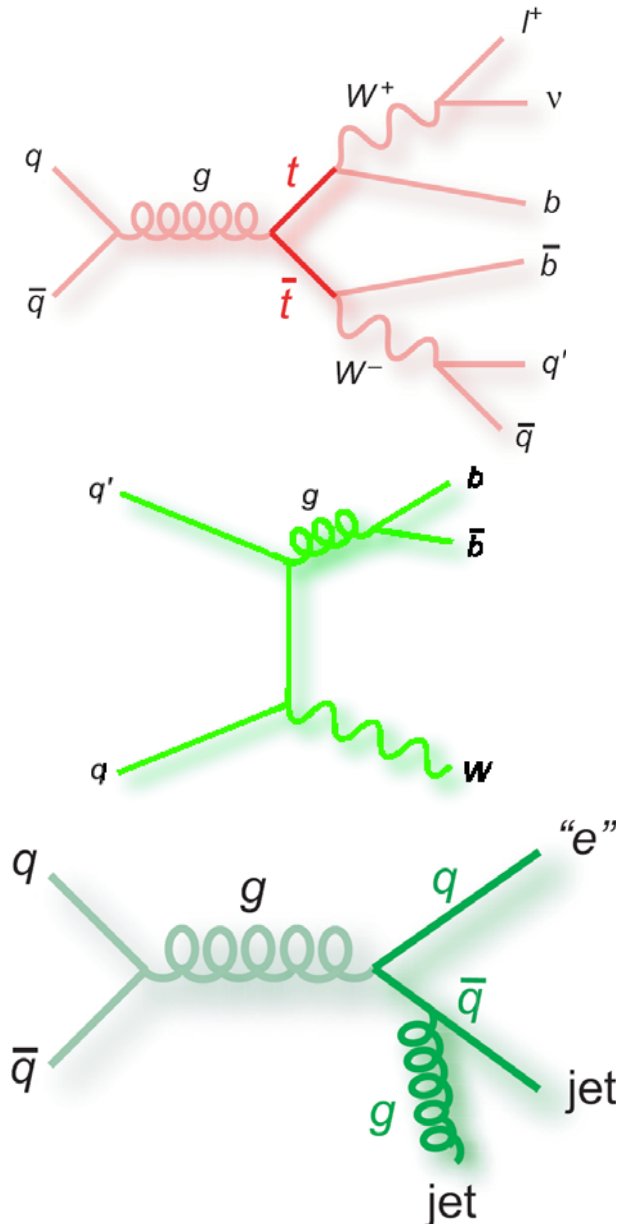
Contain a real lepton from W decay  
 $Wjj$  ( $j = g, u, d, s, c, b$ )

## Misidentified multijet events ( QCD )

Contain fake isolated electron or muon

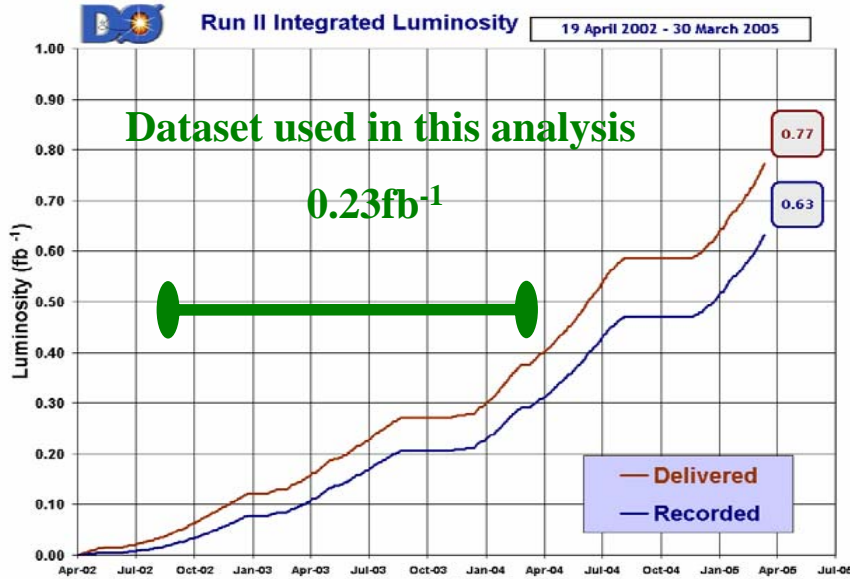
## Diboson events

WW, WZ, ZZ

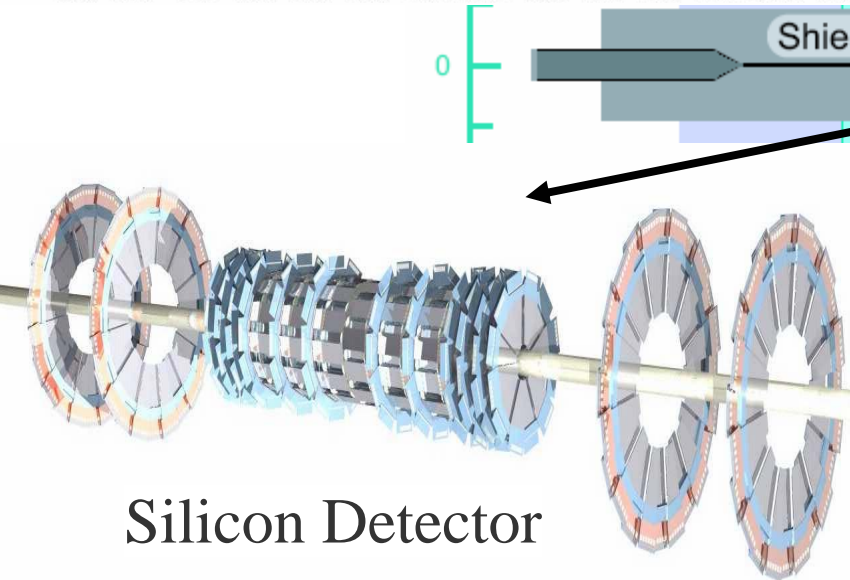
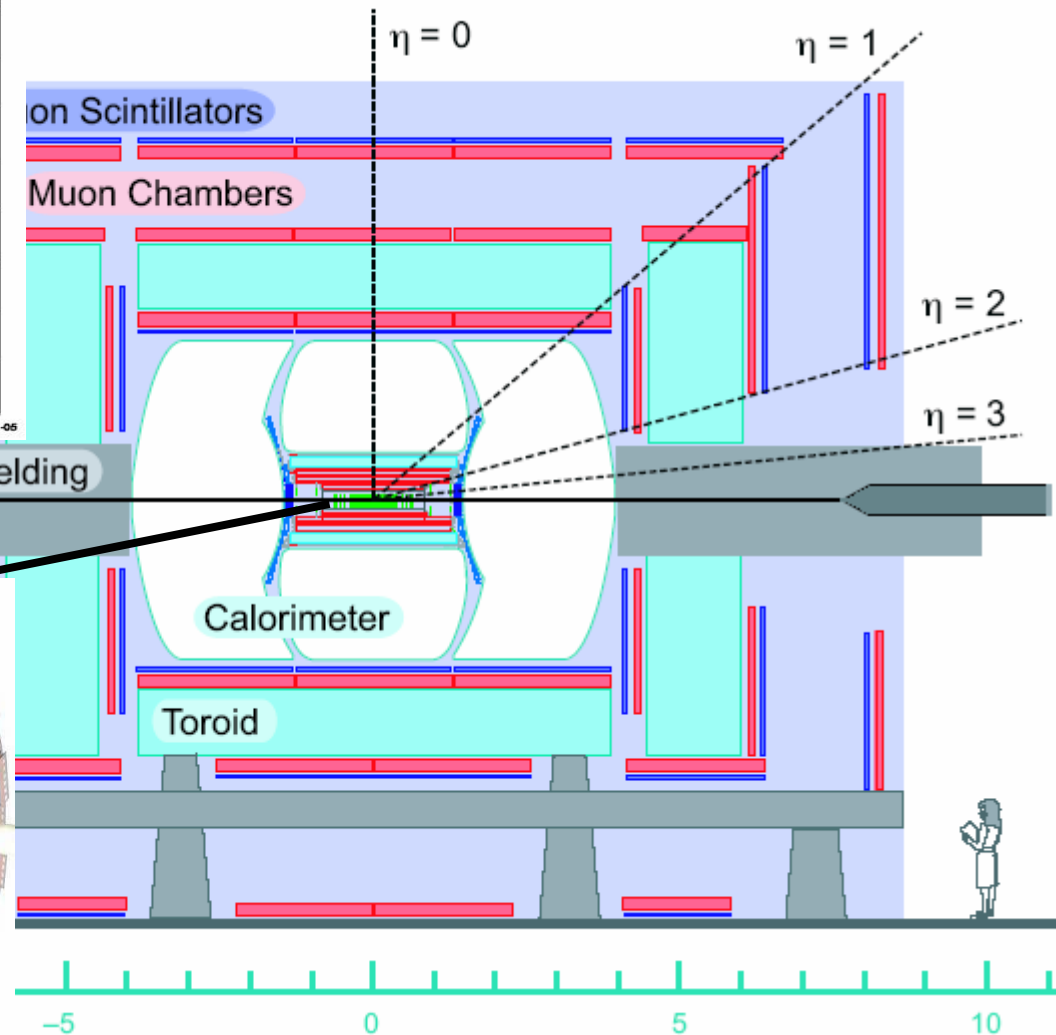




# DØ Detector and Dataset



Center of Mass Energy: 1.96 TeV





# Event Selection

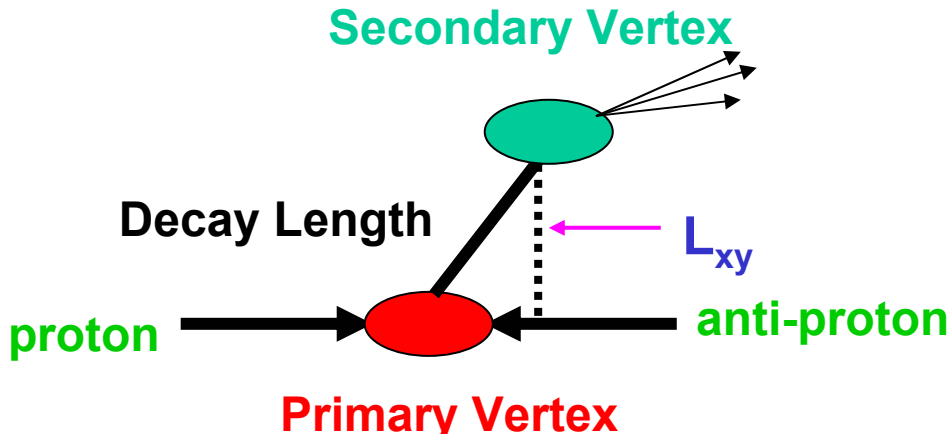
## • Requirements

- 1 isolated lepton (electron or muon)  $p_T > 20 \text{ GeV}$
- High missing transverse energy from neutrino  $\cancel{E}_T > 20 \text{ GeV}$
- Jets: one or more jets with  $|y| < 2.5$   $p_T > 15 \text{ GeV}$
- No second high  $p_T$  lepton

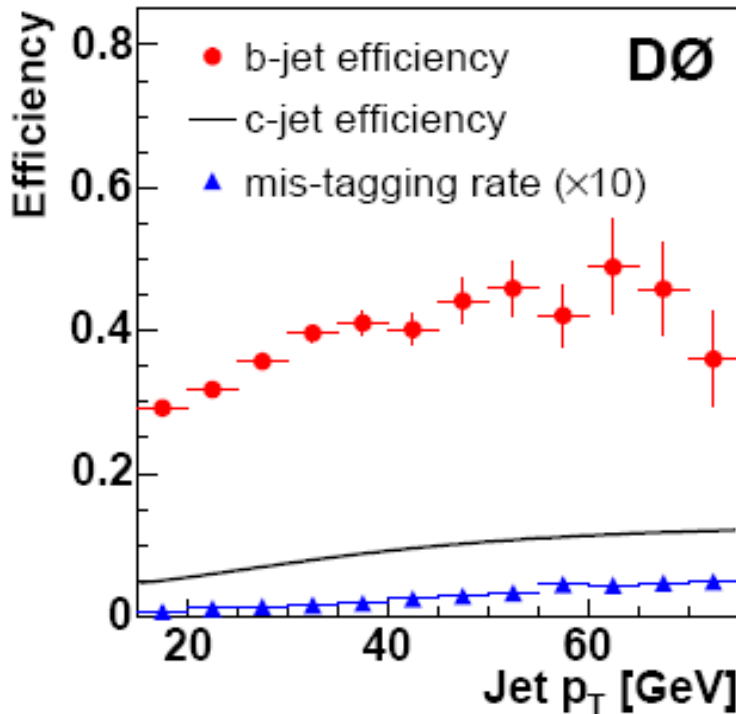
## • b-jet identification ( B-tagging )

- Secondary vertex tagging algorithm
- Three separate datasets: exactly one tagged jets, at least two tagged jets or zero tagged jets

# Secondary Vertex Tagging Algorithm



- Find a decay length,  $L$  for each vertex
- Define the decay length significance in transverse plane



$$L_{\text{significance}} = L_{xy} / \sigma_{Lxy}$$

- If  $L_{\text{significance}} > 7$ , the event passes SVT algorithm
- Tag rate  $\sim 40\%$
- Mistag rate  $\sim 0.2\%$



# Analysis Method

- Decide the ratio  $R$  and  $t\bar{t}$  cross section  $\sigma$  simultaneously
- Separate final states with (electron, muon) (3, 4jets) (0, 1, 2tags)
- Expected event numbers are fitted to observed data numbers for the 1, 2 tag channels
- Due to small  $t\bar{t}$  event numbers in the 0 tag channels topological likelihood discriminant is constructed

$$R = \frac{B(t \rightarrow Wb)}{B(t \rightarrow Wq)}$$

b-tagged jet number	0		1		2	
Jet multiplicity	3	4	3	4	3	4
	not used	topological likelihood	fit to the observed event numbers			

For electron (or muon) channel



# $t\bar{t}$ Event Tagging Probabilities

- $t\bar{t}$  event tagging probability: fraction of identified  $t\bar{t}$  event number and total  $t\bar{t}$  event number
- If R is equal to 1 the branching fraction  $B(t \rightarrow Wb)$  is 100%
- If R is less than 1 the decay of the two top quarks in a  $t\bar{t}$  event can produce either 0, 1 or 2 b quarks
- The event tagging probabilities are derived separately for the three possibilities

**Scenario 1**     $t\bar{t} \rightarrow W^+ b W^- \bar{b}$     **two b quarks**

**Scenario 2**     $t\bar{t} \rightarrow W^+ b W^- \bar{q}_l$     **one b quark one light quark**

**Scenario 3**     $t\bar{t} \rightarrow W^+ q_l W^- \bar{q}_l$     **two light quarks**





# $t\bar{t}$ Event Tagging Probabilities

number of b quarks in the final states	0	1	2
probabilities to obtain each of the three final states	$(1-R)^2$	$2R(1-R)$	$R^2$

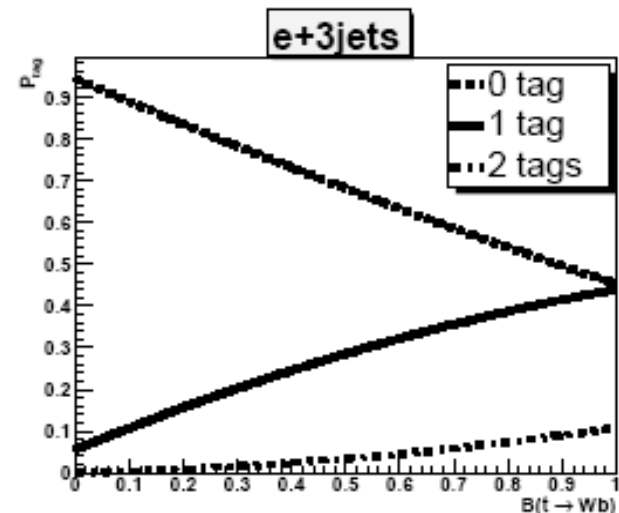
$t\bar{t}$  event tagging probability = probability to have each final state  $\times$  probability to identify each final state  
physics issue
detection issue

$$P^{n \text{ tag}}(t\bar{t}, R) = R^2 P^{n \text{ tag}}(t\bar{t} \rightarrow bb) + 2 R(1-R) P^{n \text{ tag}}(t\bar{t} \rightarrow bq_l) + (1-R)^2 P^{n \text{ tag}}(t\bar{t} \rightarrow q_l q_l)$$

- Use  $t\bar{t}$  Monte Carlo to compute the event tagging probabilities
- No Monte Carlo samples for

$$t\bar{t} \rightarrow W^+ b W^- \bar{q}_l$$

$$t\bar{t} \rightarrow W^+ q_l W^- \bar{q}_l$$





# $t\bar{t}$ event identification and R

## Scenario 2

$$t\bar{t} \rightarrow W^+ b W^- \bar{q}_l$$

$$P^{n \text{ tag}}(t\bar{t}, R) = R^2 P^{n \text{ tag}}(t\bar{t} \rightarrow bb) + 2 R(1-R) P^{n \text{ tag}}(t\bar{t} \rightarrow bq_l) + (1-R)^2 P^{n \text{ tag}}(t\bar{t} \rightarrow q_l q_l)$$

- Use standard  $t\bar{t}$  Monte Carlo
- Consider a jet matching  $\bar{b}$  from  $\bar{t}$  as light jet
- Apply light jet tagging probability to the  $\bar{b}$
- Apply b tagging probability to the other b jet from t
- Compute 0, 1 and 2 tag probabilities

## Scenario 3

$$t\bar{t} \rightarrow W^+ q_l W^- \bar{q}_l$$

- Use standard  $t\bar{t}$  Monte Carlo
- Apply light jet tagging probabilities to jets matching the b and  $\bar{b}$
- Compute 0, 1 and 2 tag probabilities

standard  $t\bar{t}$  Monte Carlo

$$t\bar{t} \rightarrow W^+ b W^- \bar{b}$$



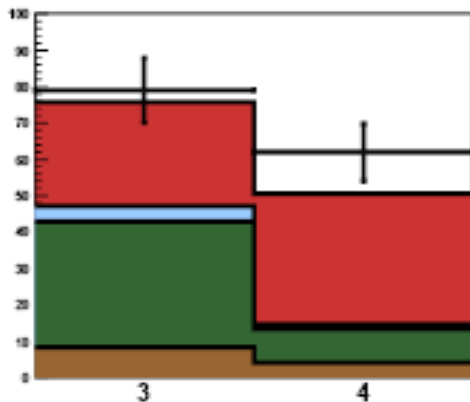
# Maximum Likelihood Fit

- $R$  and  $\sigma$  are obtained by a maximum likelihood fit to the observed number of events
- Eight different channels : electron or muon with 3 or  $\geq 4$  jets and one or two tags

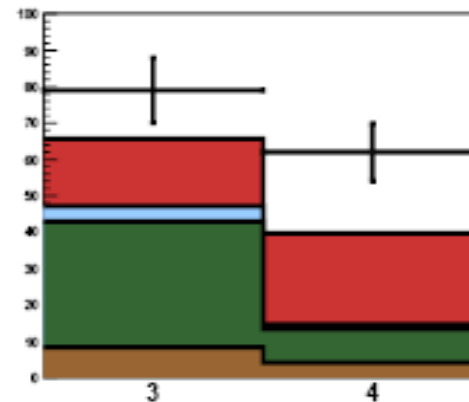
$$\mathcal{L} = \prod_i P(N_i^{obs}, N_i^{predicted} (R, \sigma))$$

- Here  $P(N^{obs}, N^{predicted})$  denotes the Poisson probability

$R = 1$



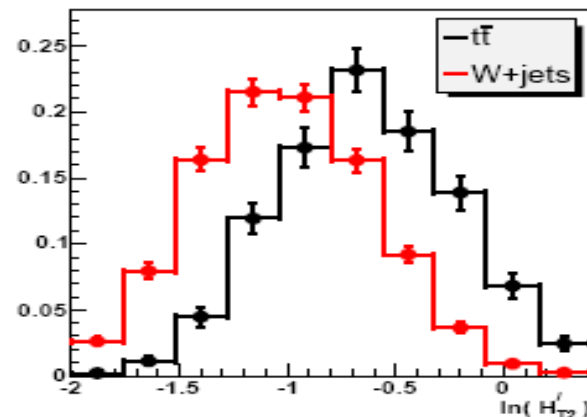
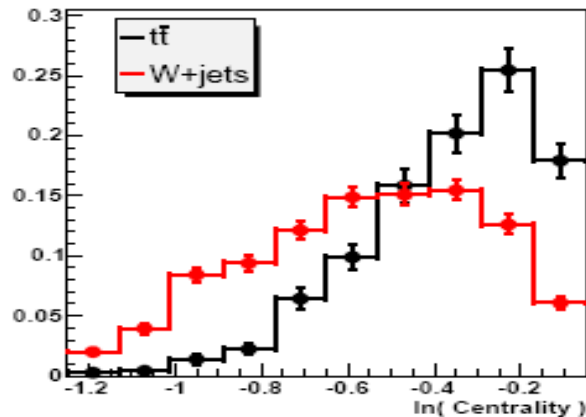
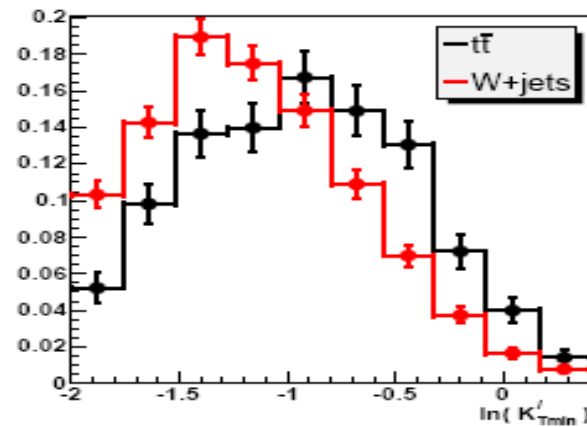
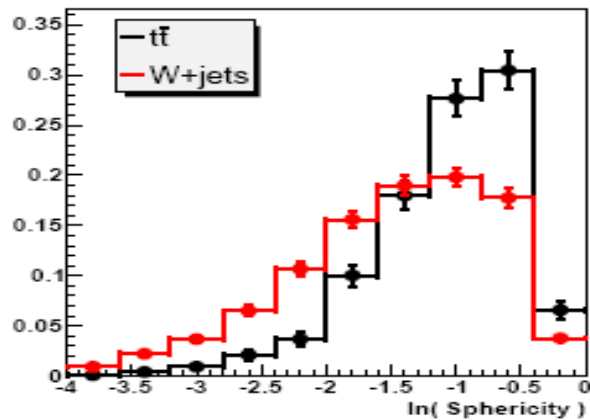
$R = 0.5$



example

# Treatment of 0 Tag Sample

- Total number of observed events in the 0 tag sample is too small to constrain  $R$  and  $\sigma$
- Use topological discriminating variables and build likelihood



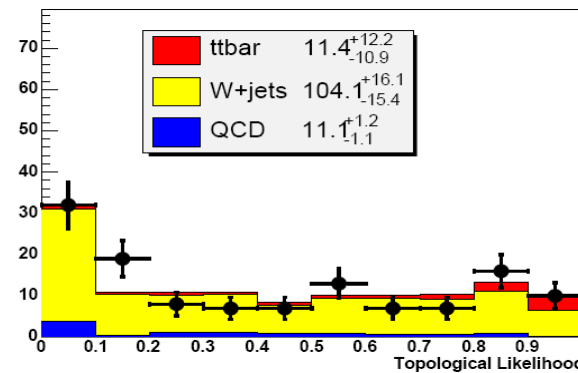
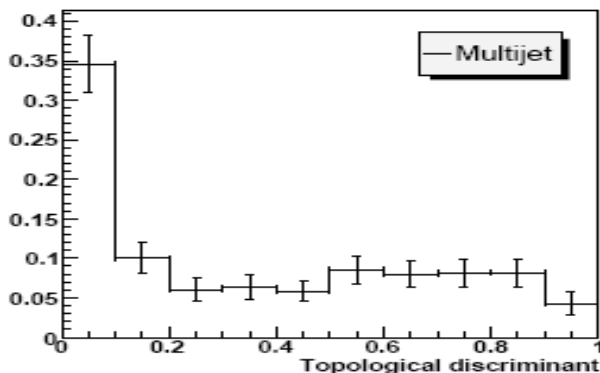
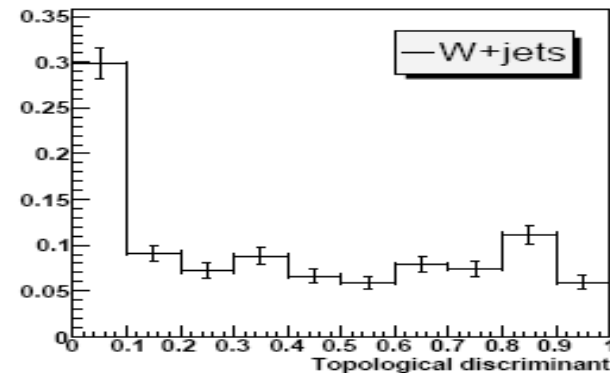
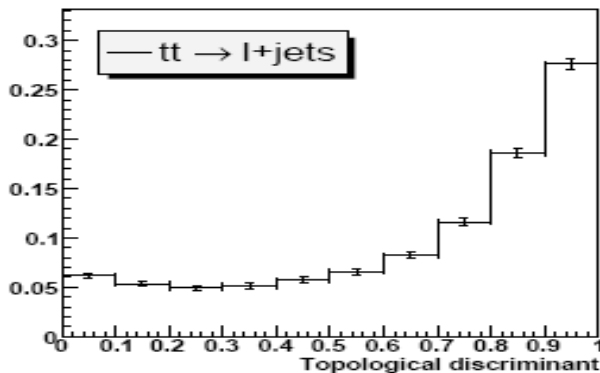
1. Sphericity
2.  $K'_{Tmin}$
3. Centrality
4.  $H'_{T2}$

# Treatment of 0 Tag Sample

- Apply only in electron or muon with  $\geq 4$  jets and 0 tag sample

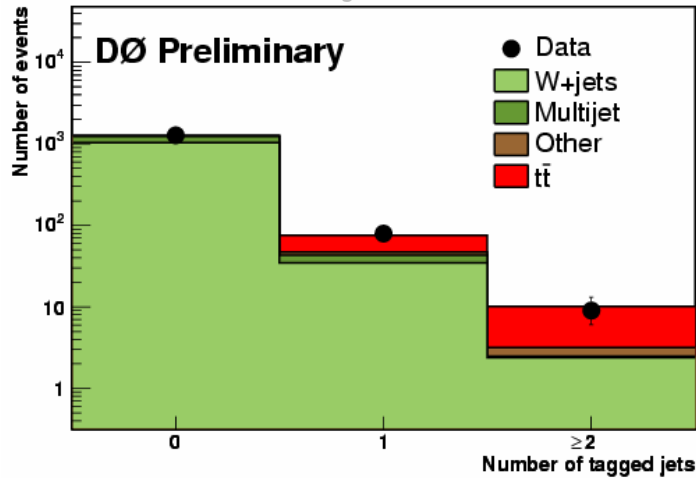
$$\mathcal{L} = \frac{S(x_1, x_2, \dots)}{S(x_1, x_2, \dots) + B(x_1, x_2, \dots)}$$

$$\approx \frac{\prod_i S_i}{\prod_i S_i + \prod_i B_i} = \frac{\prod_i S_i/B_i}{\prod_i S_i/B_i + 1} = \frac{\exp\left(\sum_i \left(\ln \frac{S_i}{B_i}\right)\right)}{\exp\left(\sum_i \left(\ln \frac{S_i}{B_i}\right)\right) + 1}$$

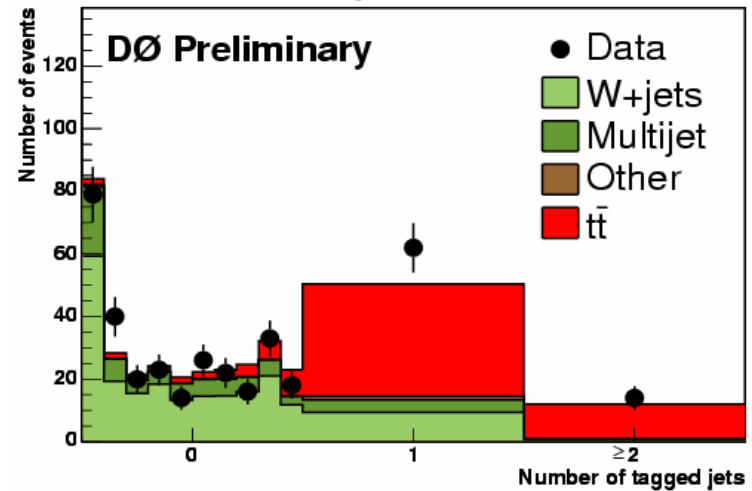


# Final Binned Likelihood Fit

$N_{\text{jet}}=3$



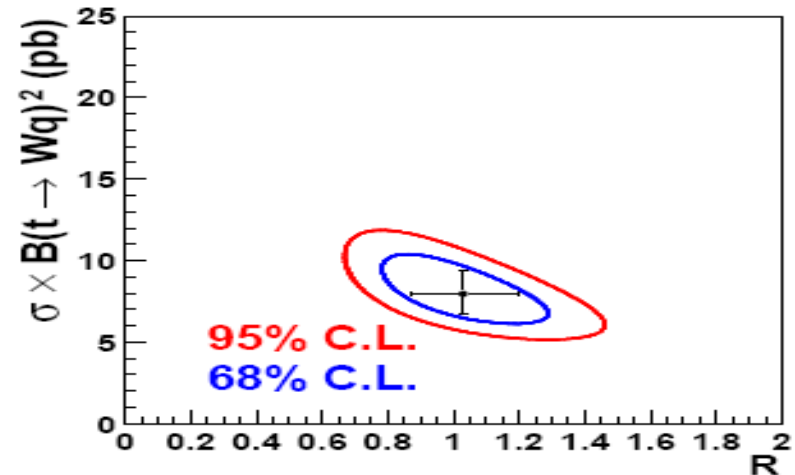
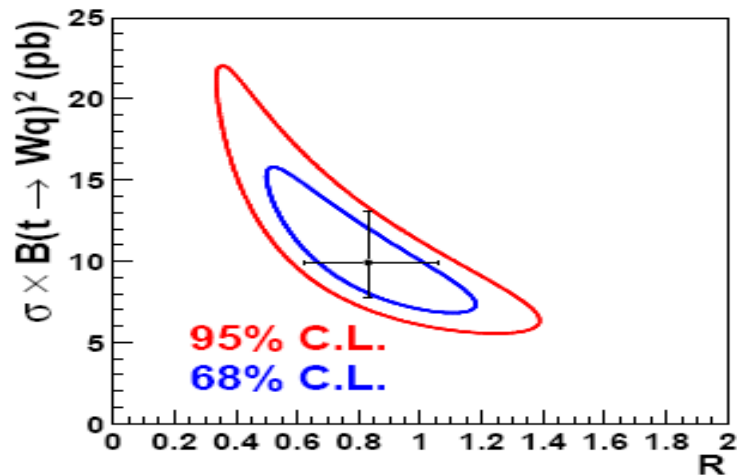
$N_{\text{jet}}\geq 4$



Improvement

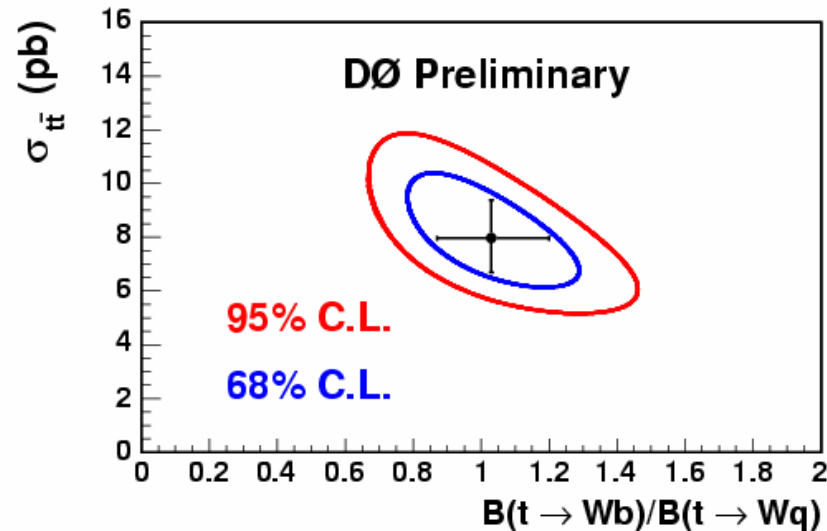
Without 0-tag

With 0-tag



# Conclusions

## • Results



- $\frac{Br(t \rightarrow Wb)}{Br(t \rightarrow Wq)} = 1.03^{+0.19}_{-0.17} (stat + syst)$

- $\sigma_{t\bar{t}} = 7.9^{+1.7}_{-1.5} (stat + syst) \pm 0.5(lumi) pb$

First measurement of R in DØ

Good agreement with the standard model expectation

Topological likelihood in the 0 tag samples make significant improvement